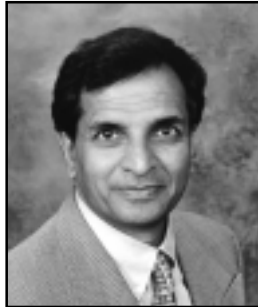


Plenary Speech 2P.2

Embedded Test Leads to Embedded Quality

Wednesday, March 28

9:25am-10:05am



Vinod Agrawal
CEO, Logic Vision

The concept of embedded test, wherein physical test engines are built right on to the semiconductor chip, has a very strong quality value throughout the life-cycle of the chip. These embedded testers can be reused throughout the lifetime of the chip from silicon debug, to characterization, to production testing (both wafer probe and final test), to board prototyping, to system integration and then finally to the diagnosis in the field.

More than 50 semiconductor and system companies worldwide are already using embedded test in their complex chips, to gain significant quality, cycle time and economic competitive advantage. This talk will explore how embedded test is becoming a standard choice for IC and system developer.

About Vinod Agrawal

Vinod K. Agarwal, Ph.D., is the founder, president and CEO of LogicVision. Vinod has more than 25 years of experience in information technology, microelectronics design and computer-aided design (CAD) software. An industry expert in digital testing, he has been active in design-for-test (DFT) and built-in-self-test (BIST) technologies for more than two decades.

He is co-inventor of several U.S. patents on BIST technology. In 1992, Vinod was elected as a fellow of the IEEE for his contributions to the field of BIST and fault tolerant computing. He has published more than 100 technical papers in international journals and conference proceedings.